Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/774,033	ELAHEE, SHAWN L.	
Examiner	Art Unit	
Daniel B. Ko	2189	

	SEARCHED				
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Plus Search	2/15/2006	DBK		
IEEE Search	2/16/2006	DBK		
ACM Search	2/16/2006	DBK		
707/202, 204 (text search only - see search history printout)	2/16/2006	DBK		
711/161, 162 (text search only - see search history printout)	2/16/2006	DBK		
EAST search (see search history printout)	2/16/2006	DBK		